

Integration of Diffraction Focussing Optics into RAY

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COST STSM, s in cooperation with:

Raytracing routine for transmission zone plates

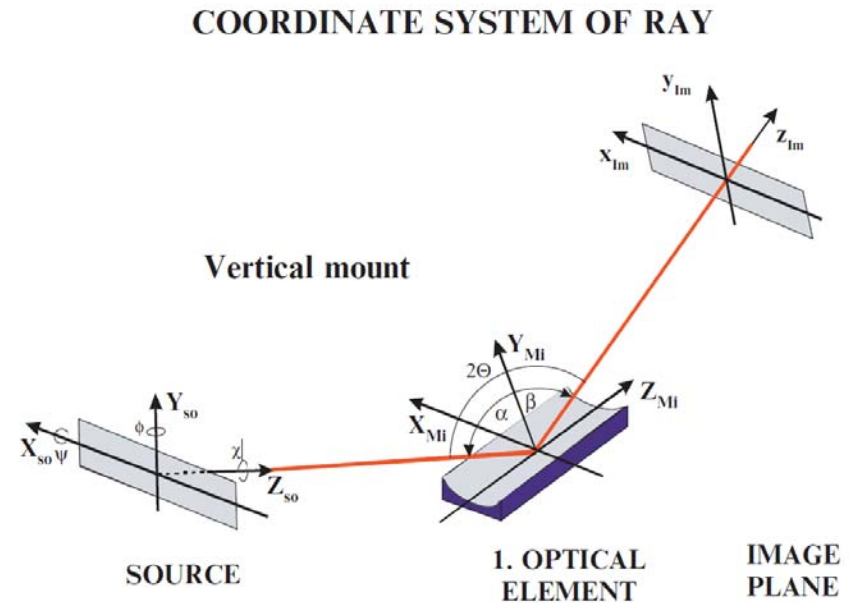
- *BESSY II:* *Franz Schäfers,
Alexei Erko,
Alexander Firsov*
- *Institute of Physics,
Academy of Sciences
of the Czech Republic:* *Nikolay Artemiev*

Raytracing routine for reflection zone plates

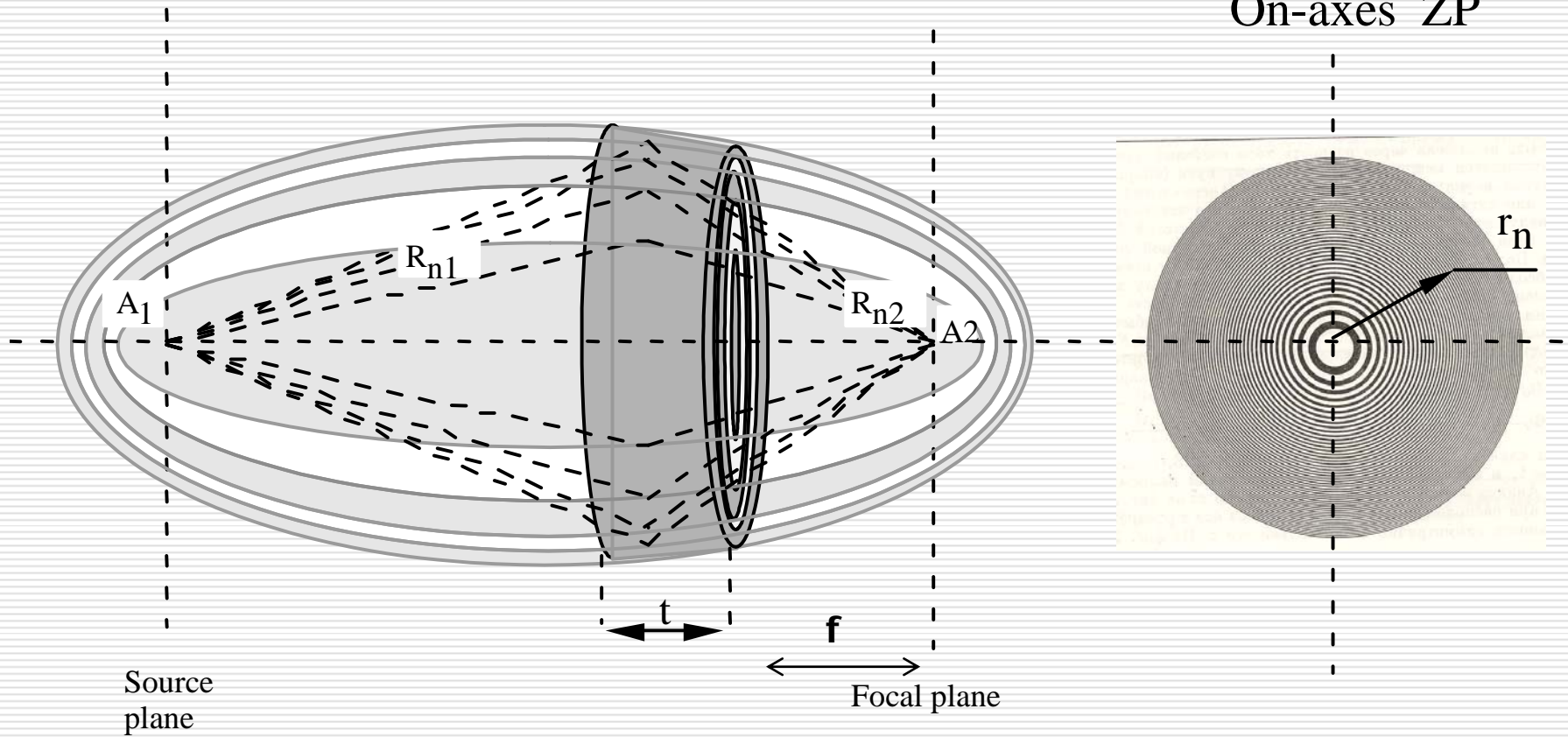
- *Kings College London, U K:* *Shahin Sahraei
Alan G. Michette*

BESSY RAY program (F. Schäfers)

- Simulate Optical systems up to 10 elements
- Beamline design tool
- Geometric Optics
- Sources
 - Point
 - Dipole
 - Undulator
- Optical elements
 - Reflection Mirrors
 - Crystals (graded)
 - Gratings (VLS)
 - Transmission Zone Plates
 - Reflection Zone plates



On-axis zone plates.



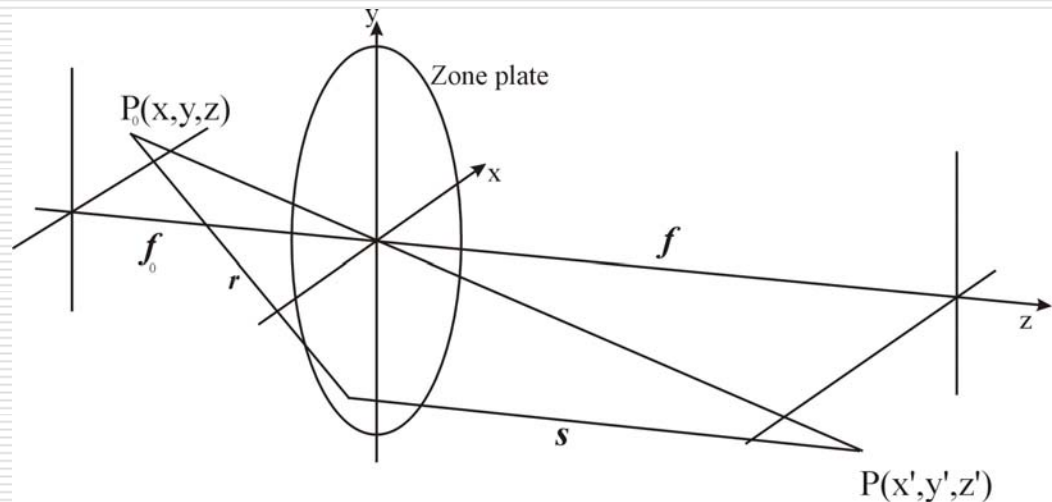
$$r_n = (n\lambda f)^{0.5}$$

Diffraction on a zone plate

Using the Fresnel – Kirchhoff diffraction integral one may obtain the forms of diffraction patterns. Referring to Figure, this gives the complex disturbance at \mathbf{P} as

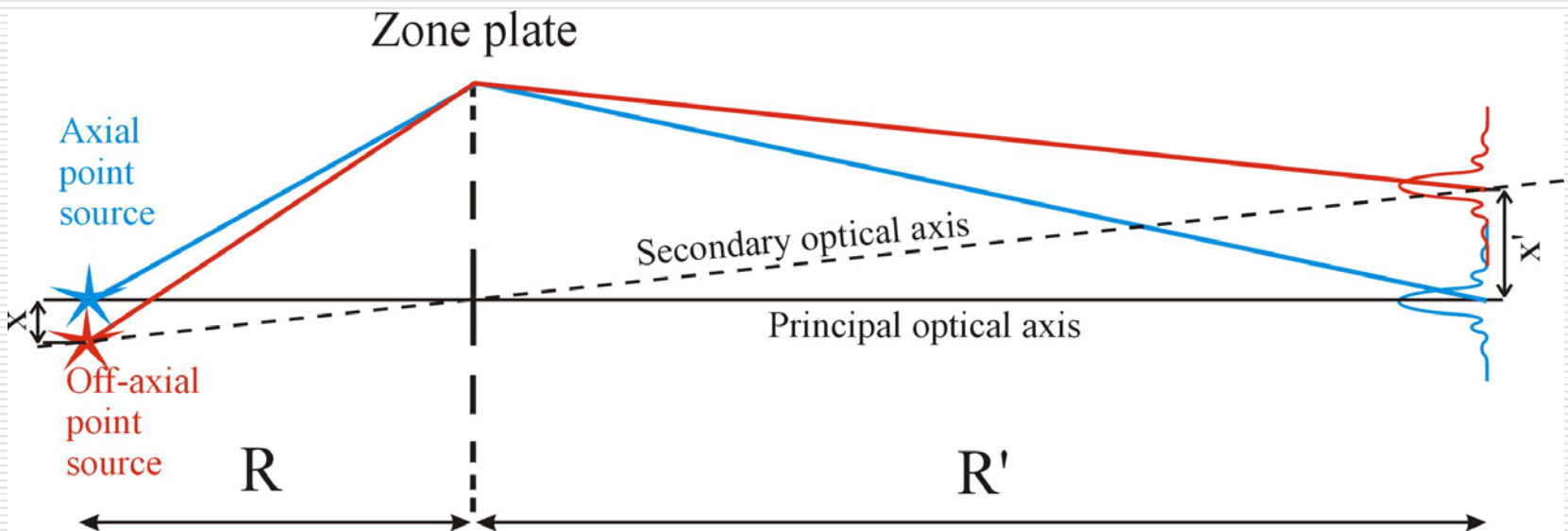
$$U(P) = -(iA/2\lambda) \cdot \iint \frac{\exp[ik(r + s)]}{r \cdot s} (\cos \alpha - \cos \beta) dS$$

The coordinate system used in the calculation of the diffraction pattern of a circular aperture.



Diffraction – raytracing transmission

Transmission from wave description to Ray description: the use of analytical solutions



INTEGRAL DIFFRACTION EFFICIENCIES

=

ray propagation probabilities

Main analytical equations

J. Kirz formulas:

$$E_m = [1/(\pi^2 m^2)] * [1 + \exp(-2\chi\Delta\phi) - 2\cos(\Delta\phi) - \exp(-\chi\Delta\phi)];$$

The maximum of the function E_m

$$\sin(\Delta\phi_{opt}) + \chi [(\cos(\Delta\phi_{opt}) \exp(-\chi\Delta\phi_{opt}))] = 0;$$

$\Delta\phi_{opt}$ is the optimal phase shift in zone plate material.

$$t_{opt} = \Delta\phi_{opt} / (2\pi\delta); \quad \chi = \delta/\beta$$

zero order diffraction E_0 and absorbed intensity E_{abs} :

$$E_0 = 0.25 [1 + \exp(-2\chi\Delta\phi) + 2\cos(\Delta\phi) \exp(-\chi\Delta\phi)];$$

$$E_{abs} = 0.5 [1 - \exp(-2\chi\Delta\phi)].$$

Raytracing model

Ray propagation probabilities.

$$E_{lost} = E_{abs} + \sum_{m=-\infty}^{m=-1} E_m + \sum_{m=5}^{m=\infty} E_m$$

$$m = 1; 3; 5$$

$$E_m = I_m / I_{in} = [1/(\pi^2 m^2)] * [1 + \exp(-2\chi\Delta\phi) - 2\cos(\Delta\phi) - \exp(-\chi\Delta\phi)];$$

Diffraction – limited resolution model

DIFFRACTION LIMITED RESOLUTION

=

ray propagation probabilities

The solution of the Fresnel – Kirchhoff diffraction integral can be found in a form of the Bessel function of first order with an argument

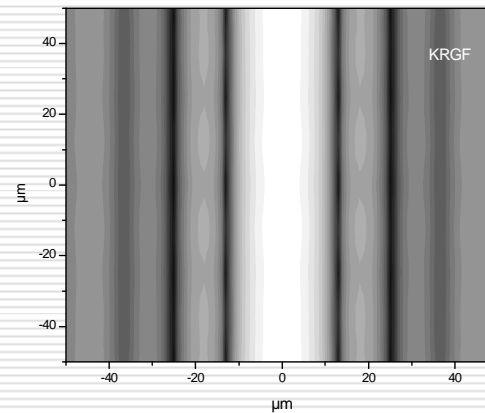
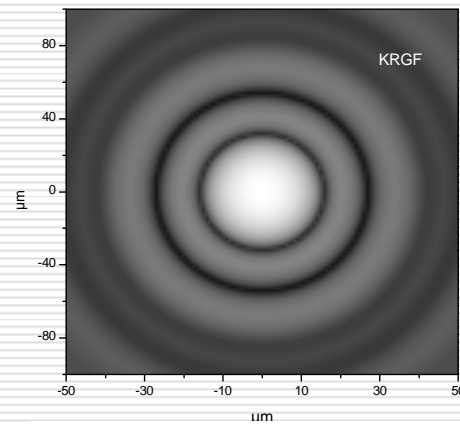
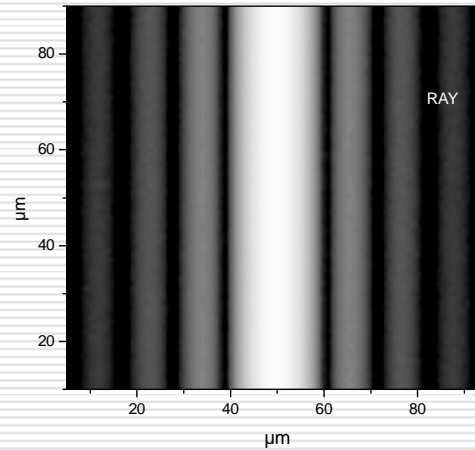
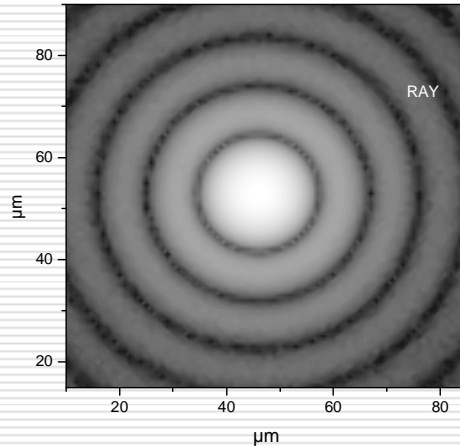
$$v_m = rN k (r' / F_m);$$

where r' the radial distance between the optical axis and an arbitrary point in the image plane. In our case $r' = x'$.

the radial intensity distribution at the focus of a zone plate is well described by an Airy pattern analogous to a perfect thin lens:

$$E_m^{-}(v_m) \sim [2J_1(v_m) / v_m]^2$$

TEST OF THE COMPUTER CODE



A focal plane of circular (a) and linear (b) zone plates calculated using programs RAY (Up) and KRGF (bottom).

Zone plate type

Linear

Circular

First order focal length F_1

1000 mm

1000 mm

Aperture

1 mm x 1 mm

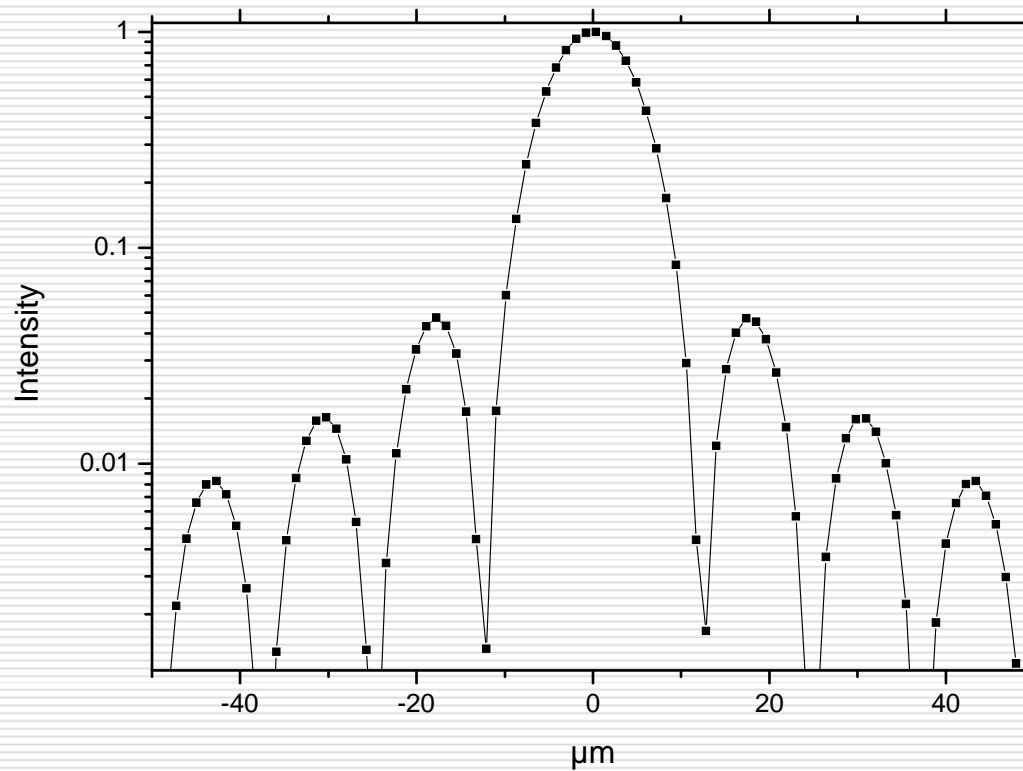
\varnothing 1 mm

R1 / R2

2000 mm / 2000 mm

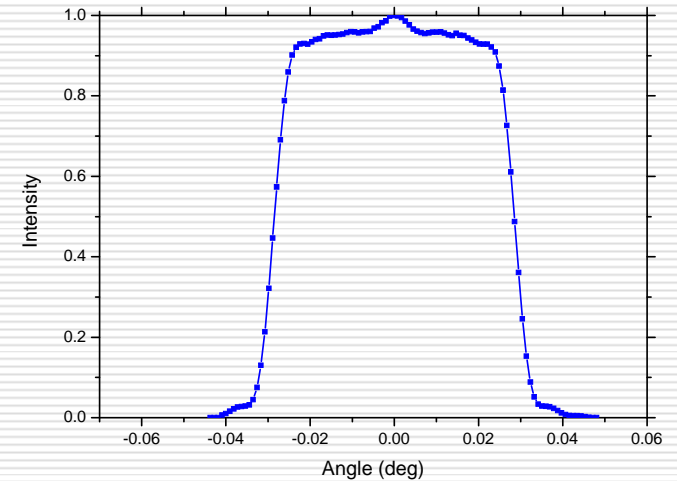
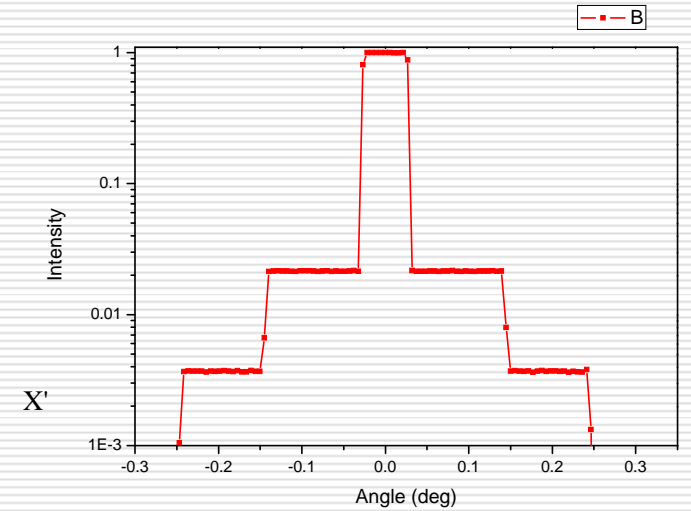
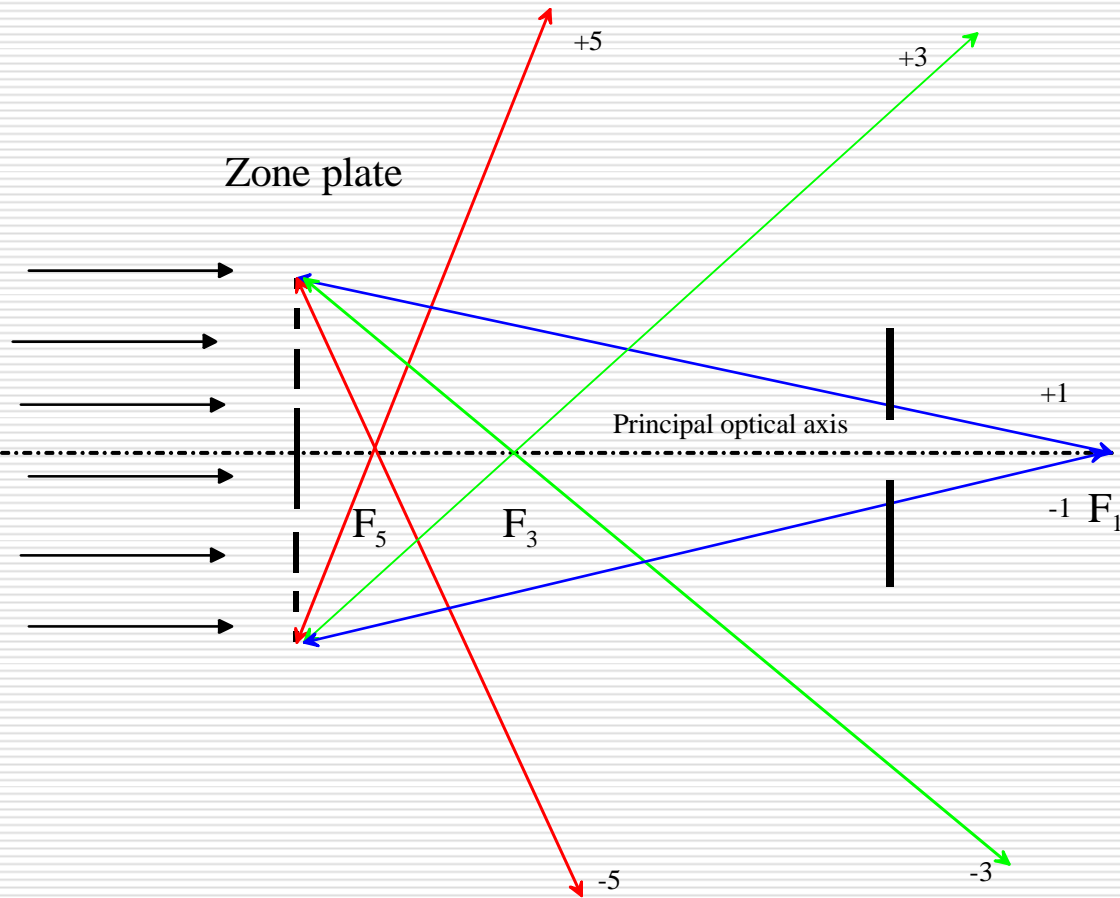
2000 mm / 2000 mm

Diffraction limited resolution



Intensity profile in the focal plane of the zone plate calculated by the RAY. 100 000 000 rays.

Spatial frequency spectra

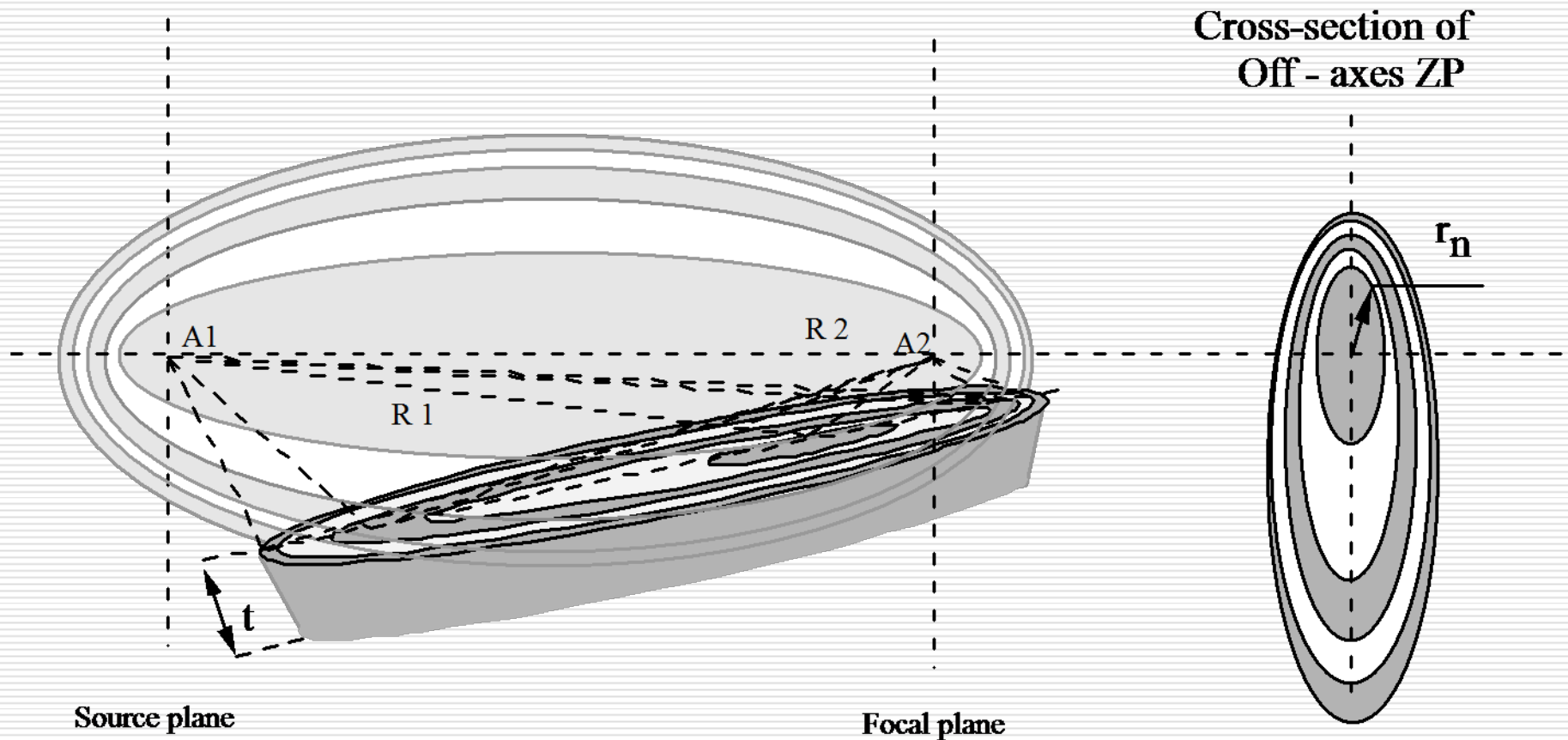


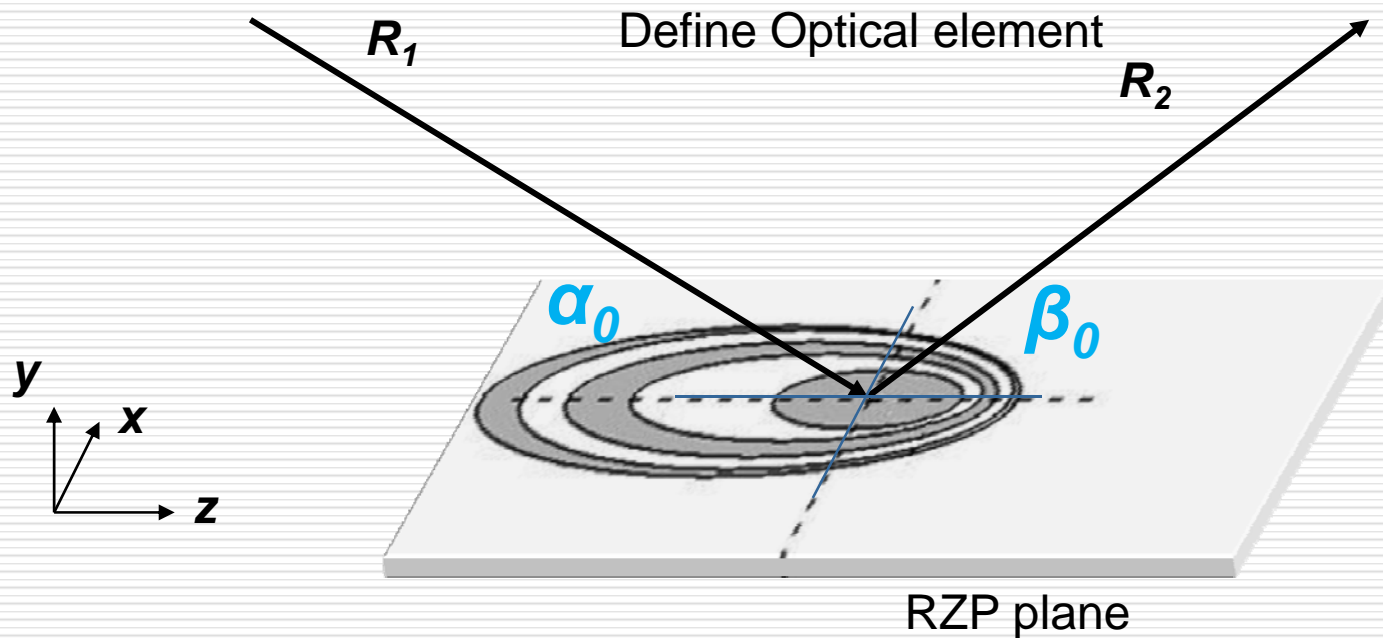
Ray-tracing Routine for Reflection Zone Plates

**Shahin Sahraei, Alan Michette, Alexei
Erko, Franz Schäfers**

**King's College London
BESSY GmbH**

Elliptical Reflection (Bragg-Fresnel) zone plate



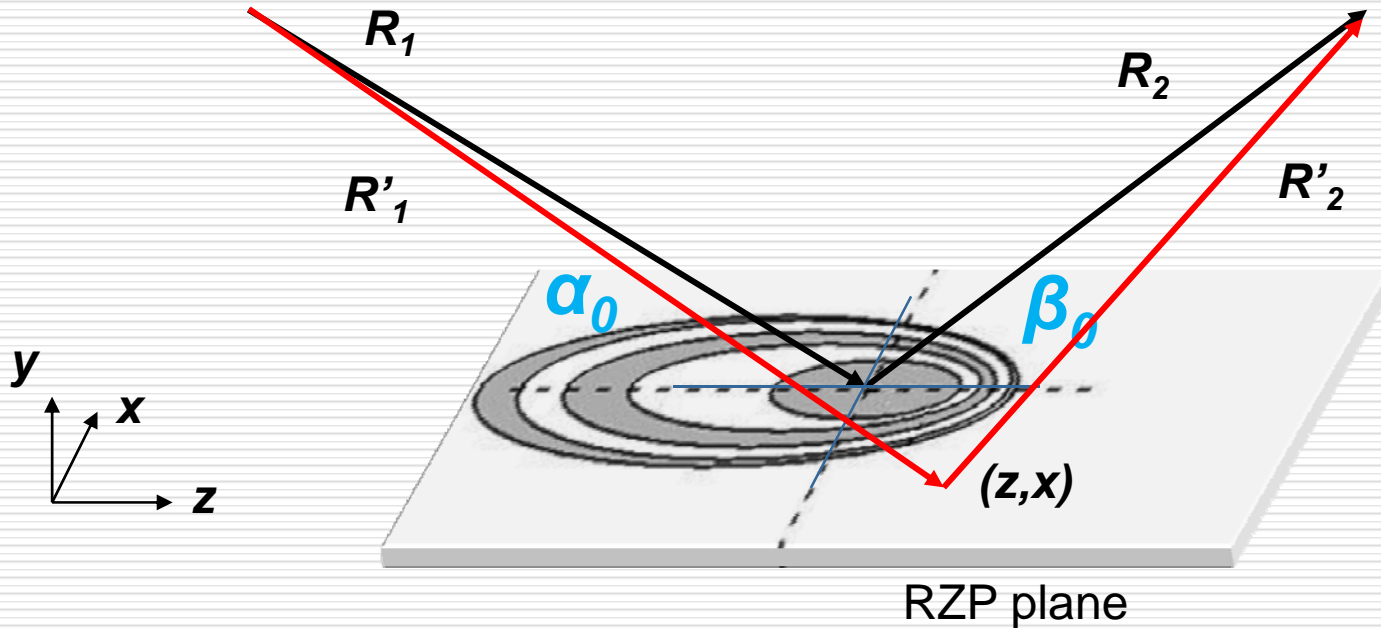


Parameters to define RZP

- Entrance arm length
- Exit arm length
- Grazing angle $\beta_0 = \alpha_0$

RAY parameters definition

Figure from Shahin Shahraei

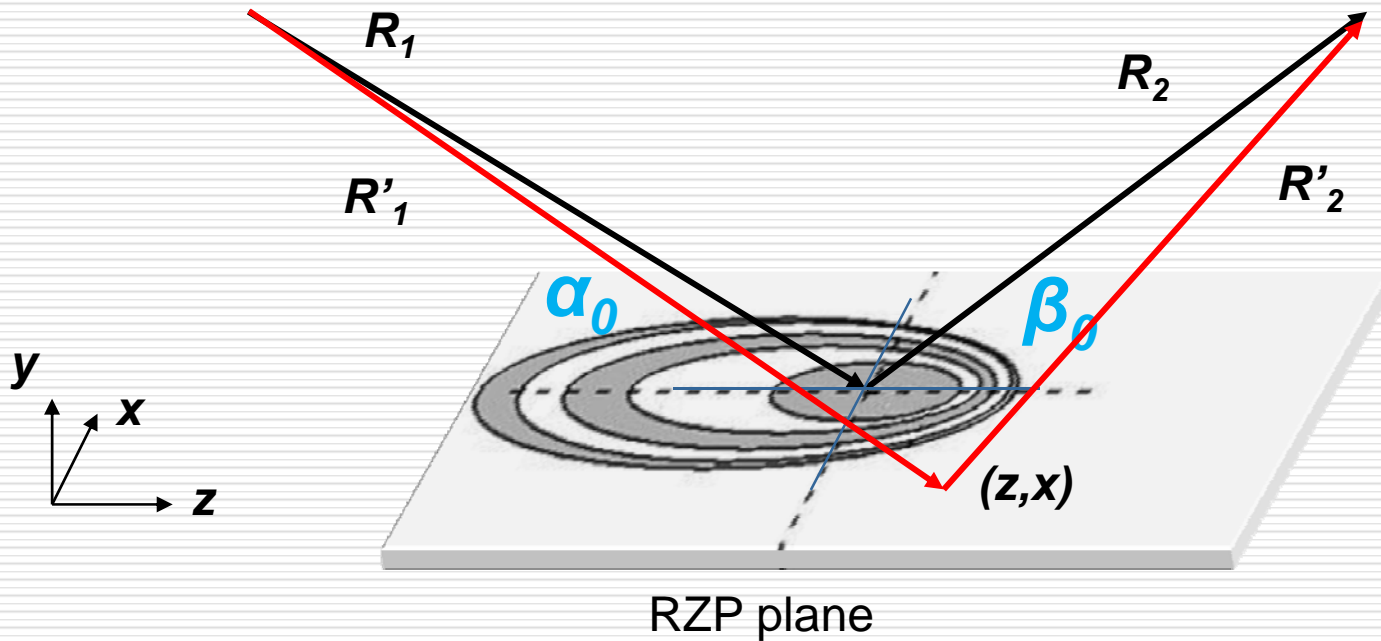


R' from user parameters

$$R_1^2 = (R_2 \cos(\alpha_0) + z)^2 + x^2 + (R_2 \sin(\alpha_0))^2$$

$$R_2^2 = (R_2 \cos(\alpha_0) - z)^2 + x^2 + (R_2 \sin(\alpha_0))^2$$

Vector model definition

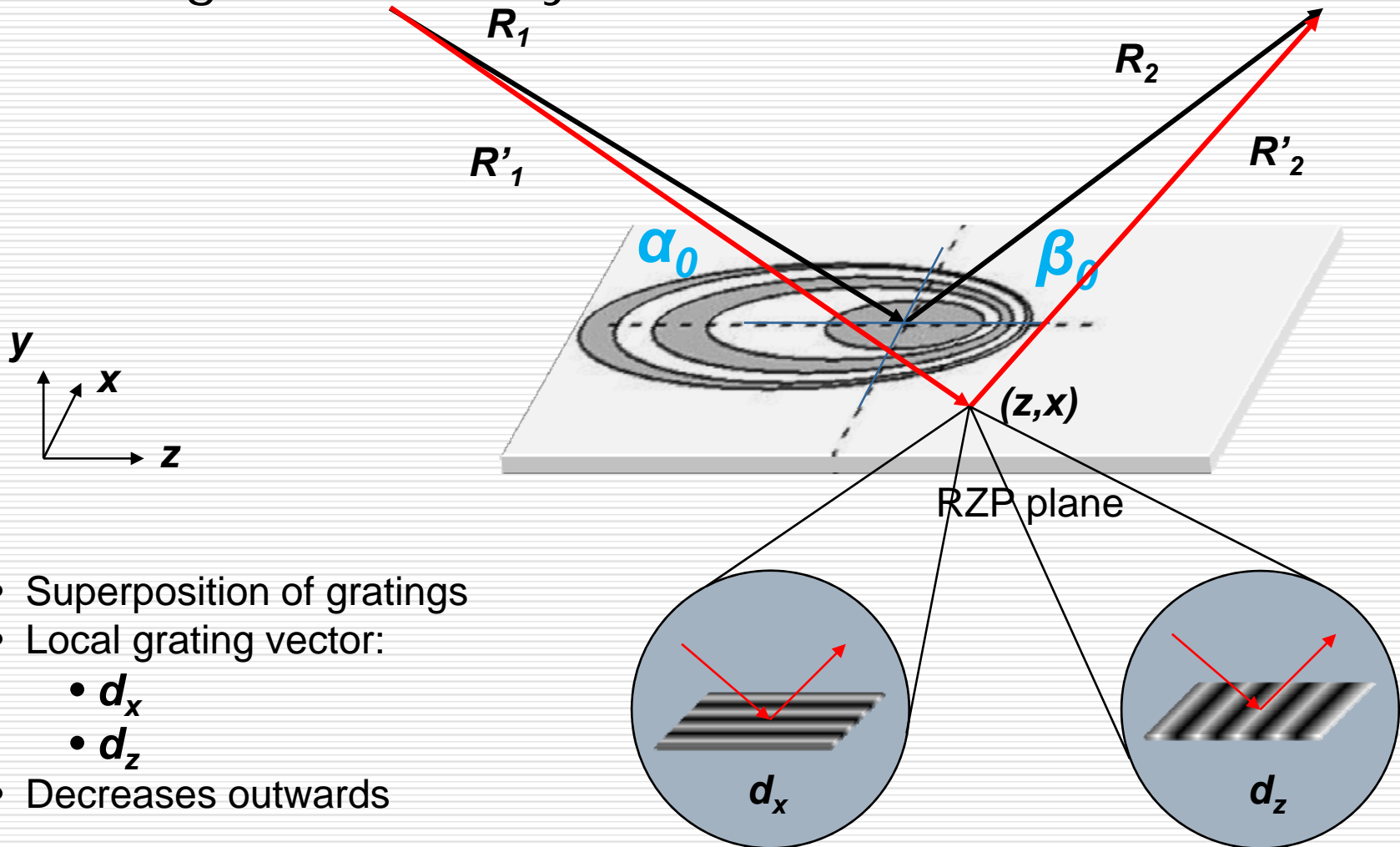


Direction cosines

Incident	$\cos \alpha_z = \frac{R_1 \cos(\alpha_0) + z}{R'_1}$	$\cos \alpha_x = \frac{x}{R'_1}$	$\cos \alpha_y = \frac{R_1 \sin(\alpha_0)}{R'_1}$
Diffracted	$\cos \beta_z = \frac{R_2 \cos(\alpha_0) - z}{R'_2}$	$\cos \beta_x = \frac{x}{R'_2}$	$\cos \beta_y = \frac{R_2 \sin(\alpha_0)}{R'_2}$

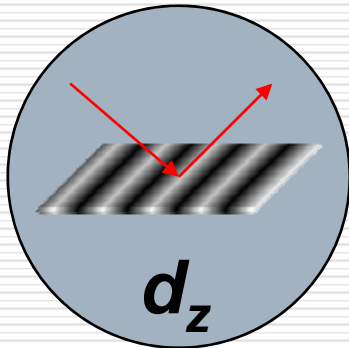
Main calculation principle

Grating subroutine by Michel Nevriere

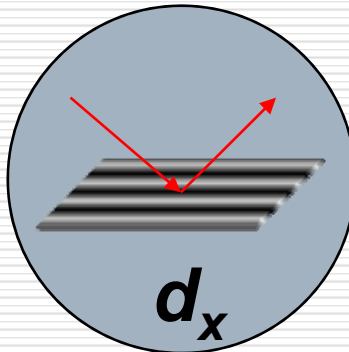


- Superposition of gratings
- Local grating vector:
 - d_x
 - d_z
- Decreases outwards

Superposed gratings vector parameter



$$DZ = \frac{1}{d_z} = \frac{1}{m\lambda} \left(\frac{R_1 \cos(\alpha_0) + z}{R'_1} - \frac{R_2 \cos(\alpha_0) - z}{R'_2} \right)$$



$$DX = \frac{1}{d_x} = \frac{1}{m\lambda} \left(\frac{x}{R'_1} + \frac{x}{R'_2} \right)$$

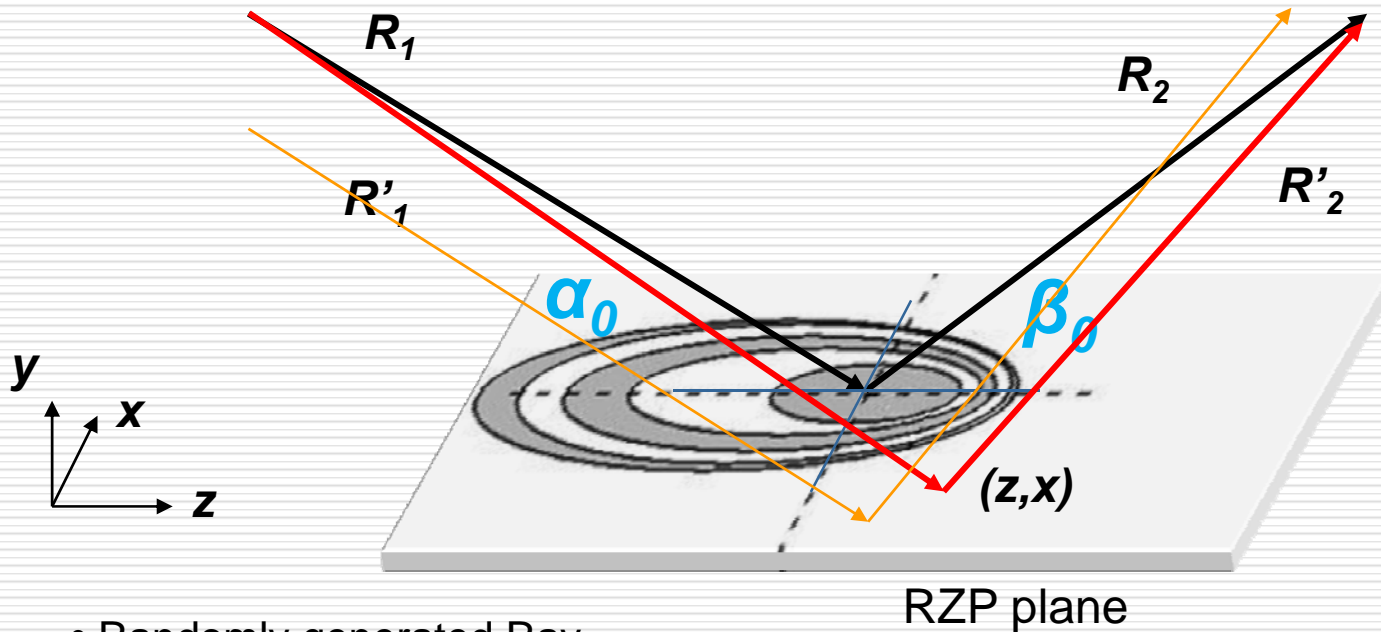
Determine Line density

- Direction Cosines
- Design energy

Figure from Shahin Shahraei

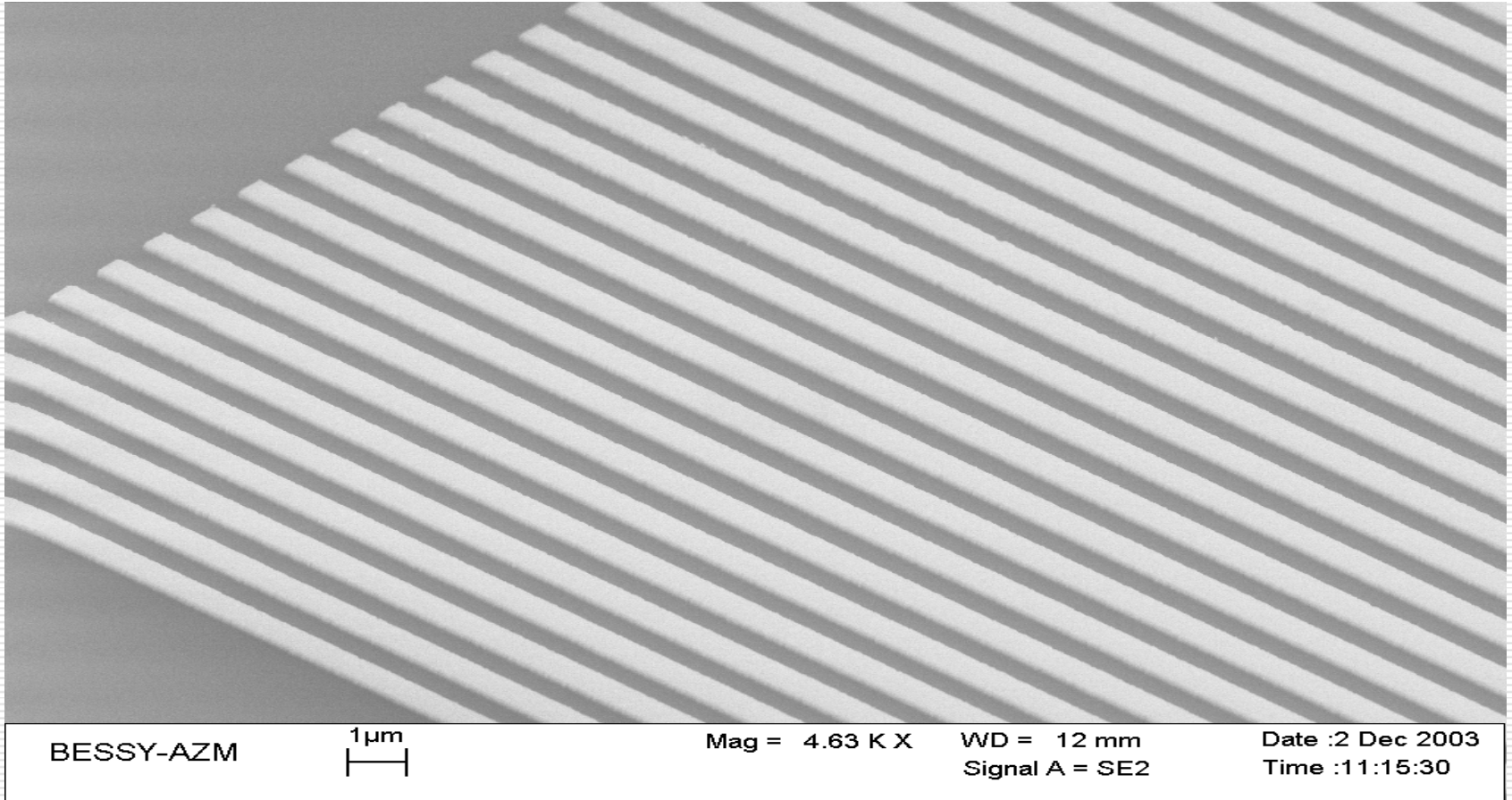
Ray subroutines functions

Figure from Shahin Shahraei



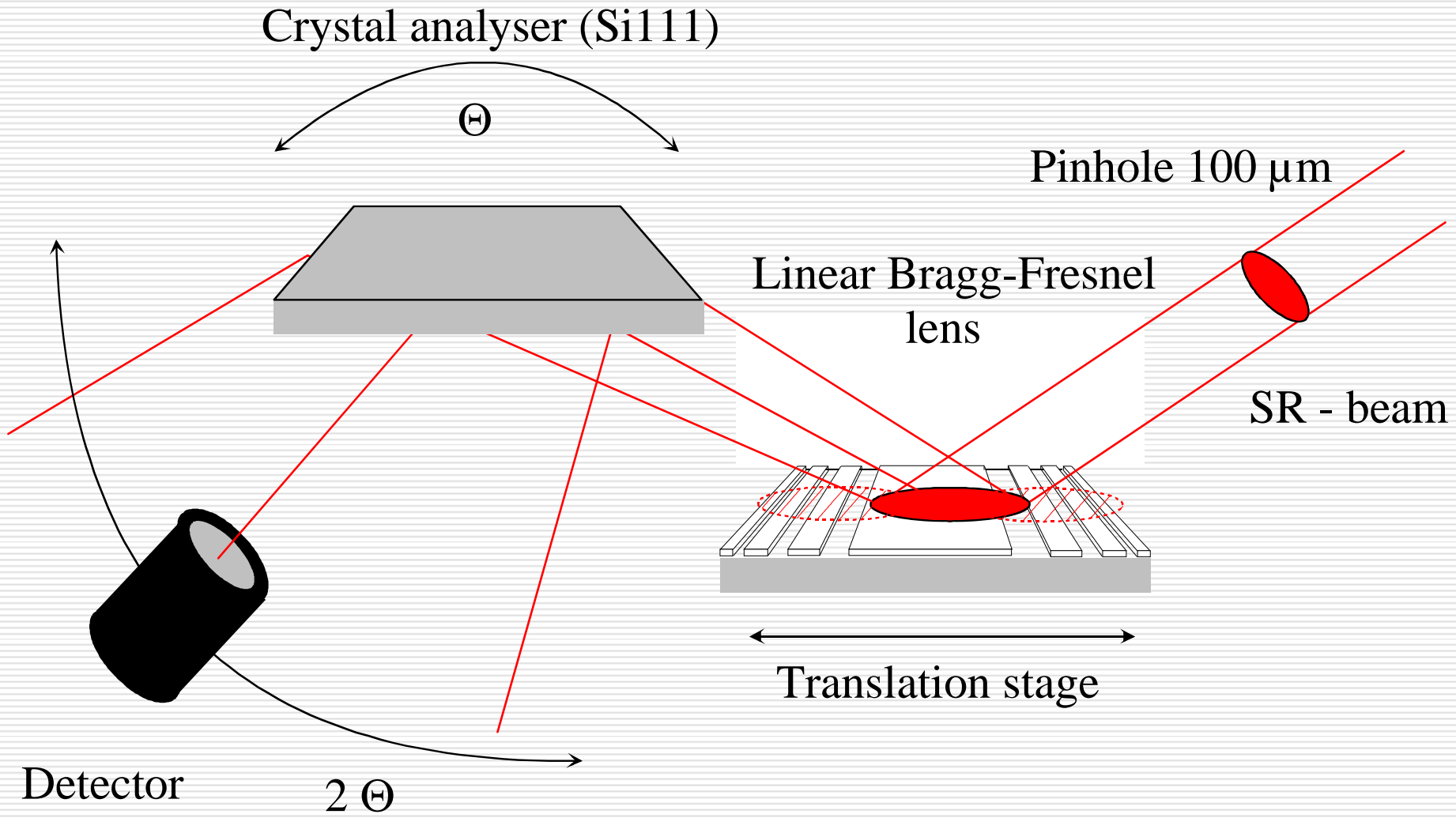
- Randomly generated Ray
 - Position within source size
 - Direction cosines within divergence
- Calculate DX, DZ at intercept
- Determine direction cosines of diffracted ray from grating subroutine

Ray RZP code application: Bragg-Fresnel Lens

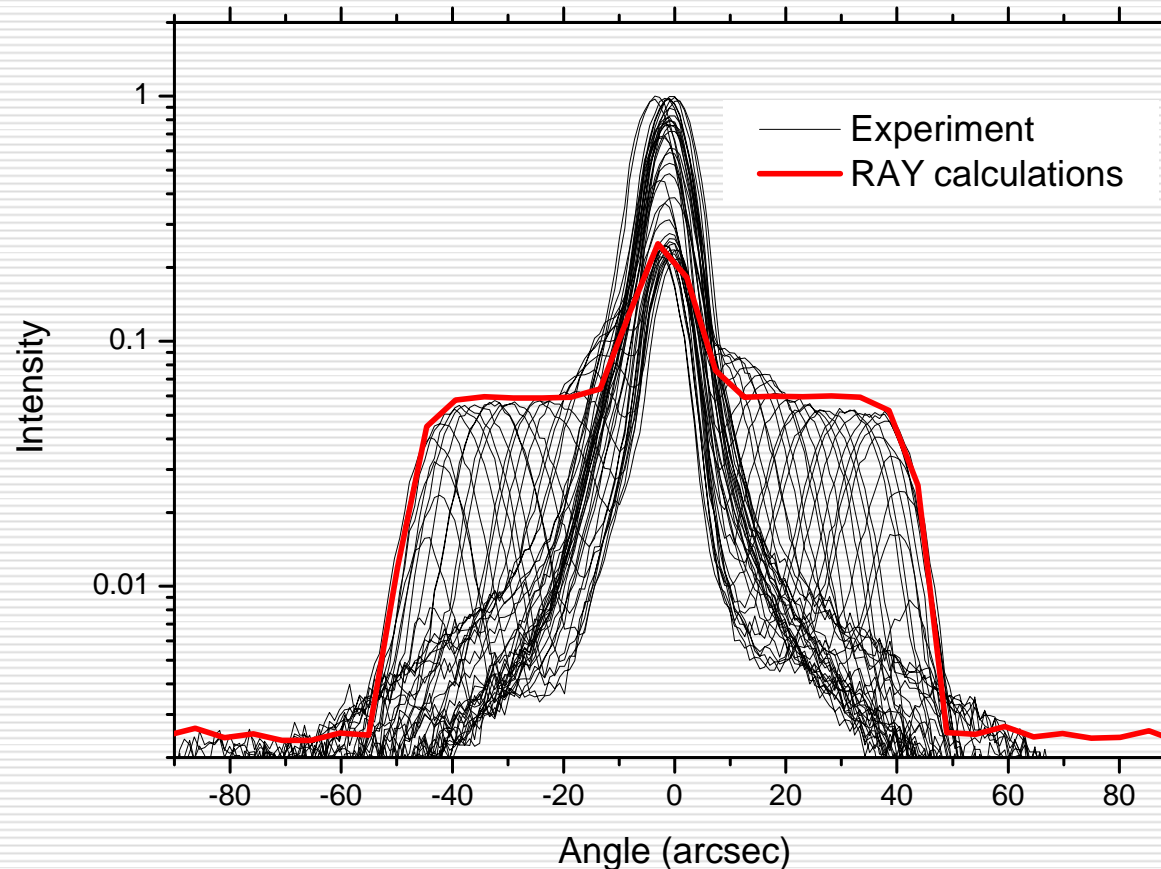


Last zones of the linear BFL on a Si 111 crystal surface (A. Firsov)

Bragg-Fresnel linear lens measurements



Bragg-Fresnel lens Spatial frequency spectra



Bragg-Fresnel lens parameters:

Focal distance: 1 m

Minimum zone width: 1.47 μm

Energy : 8500 eV

Bragg angle: 13.45°

Au thickness: 200 nm

Corresponding **normal-incidence zone plate** parameters:

Focal distance: 1 m

Minimum zone width: 0.34 μm

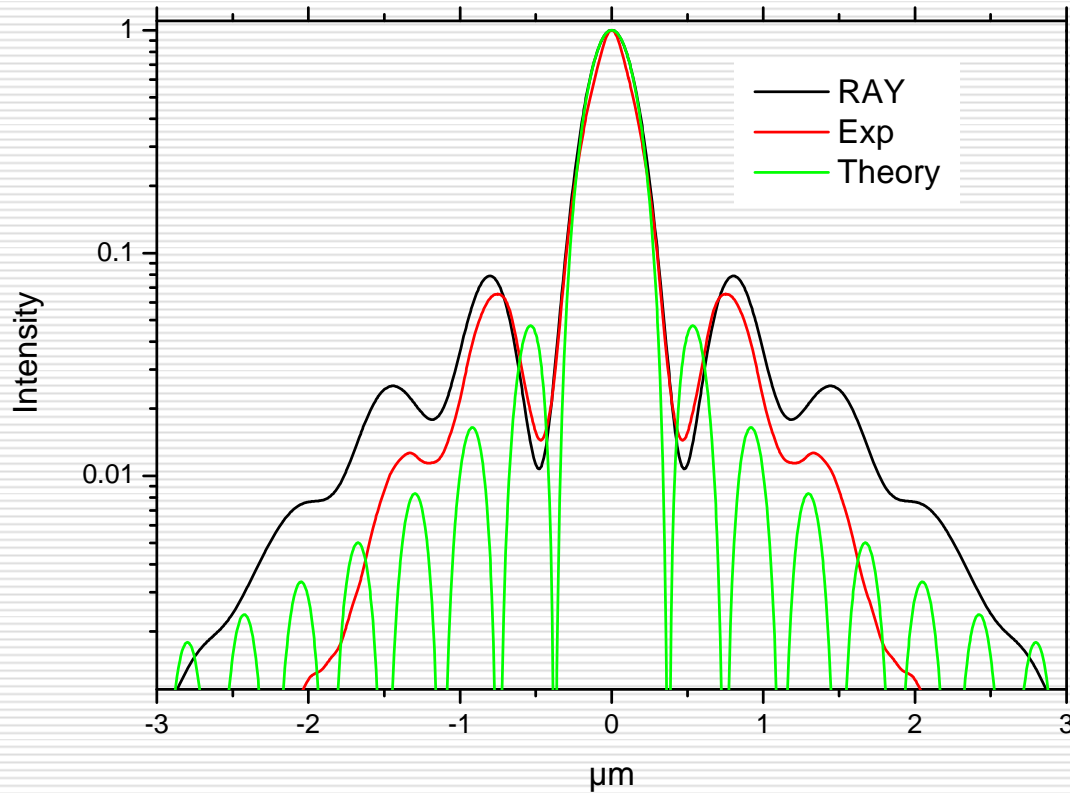
Energy : 8500 eV

Bragg angle: 90°

Au thickness: 1350 nm

Beam divergence: 4.5 arc sec

Calculations and measurements of a spatial resolution



Fourier transformation of the spatial frequency spectrum.

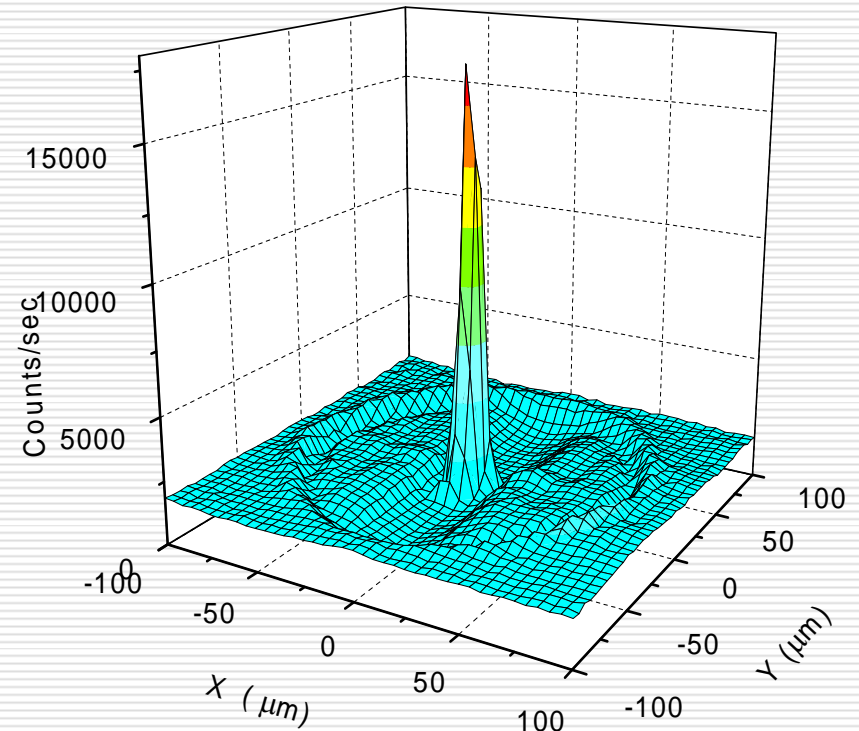
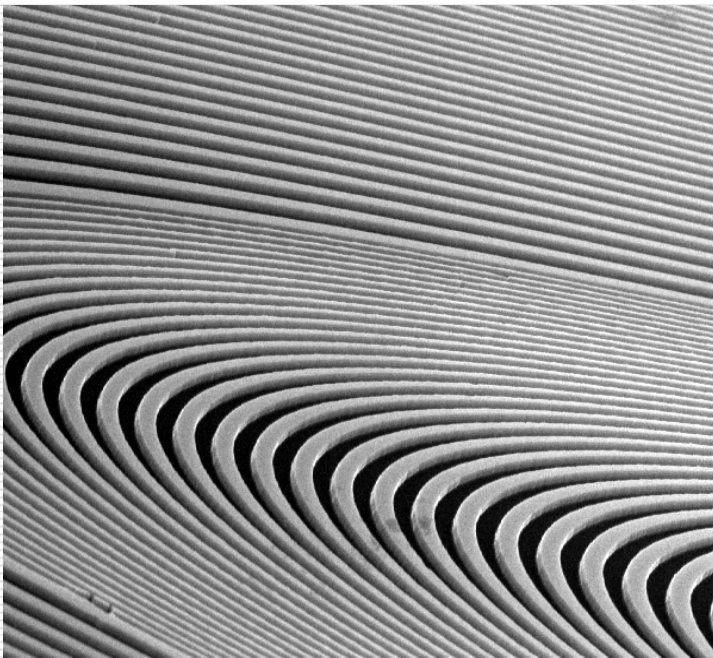
Experimental measurements and Ray model with beam divergence of 4.5''

FWHM = 0.38 μm

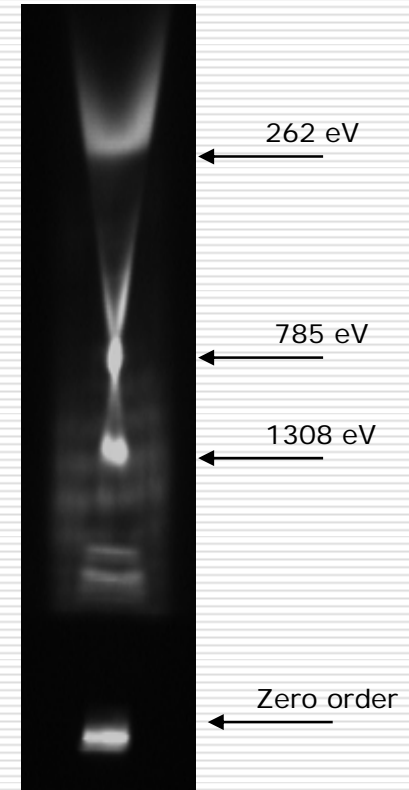
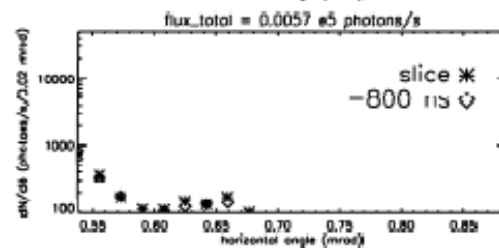
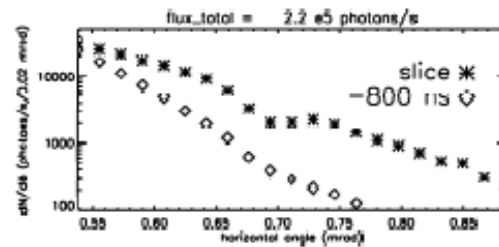
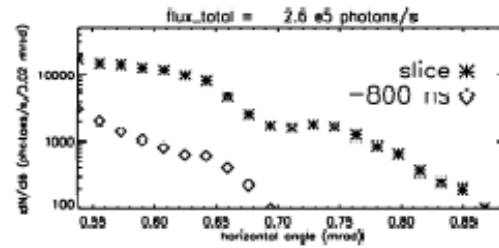
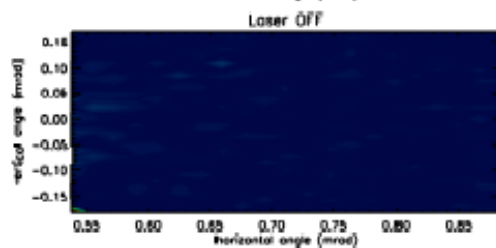
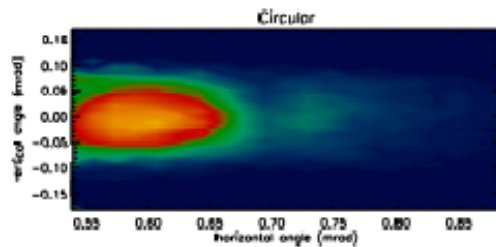
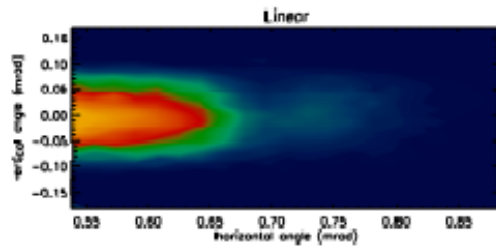
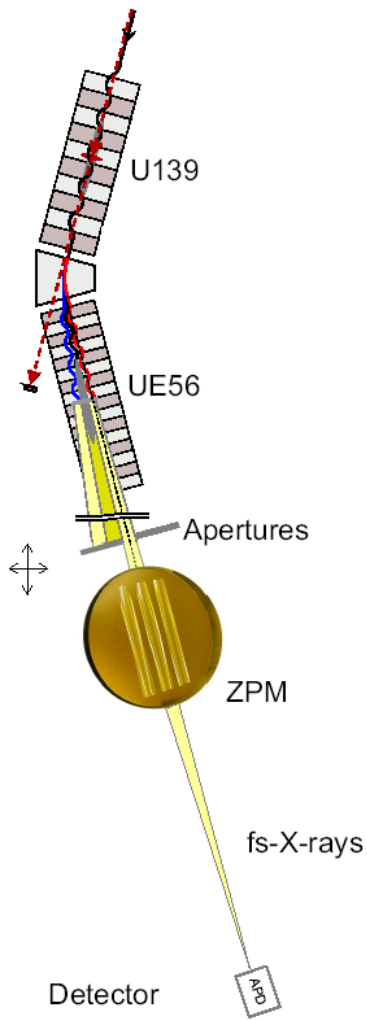
Minimum zone 1.47 μm

Synthetic holograms. Bragg-Fresnel optics.

Elliptical Bragg-Fresnel Lens based on Si (111) with extended first and third diffraction orders. Dimensions: 3000μ by 484μ ; last zone size – 0.3μ .



Reflection Zone Plates map sliced photons

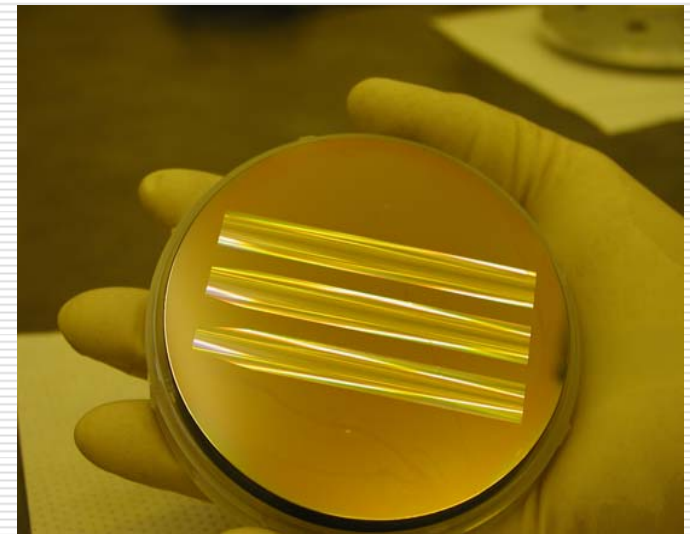
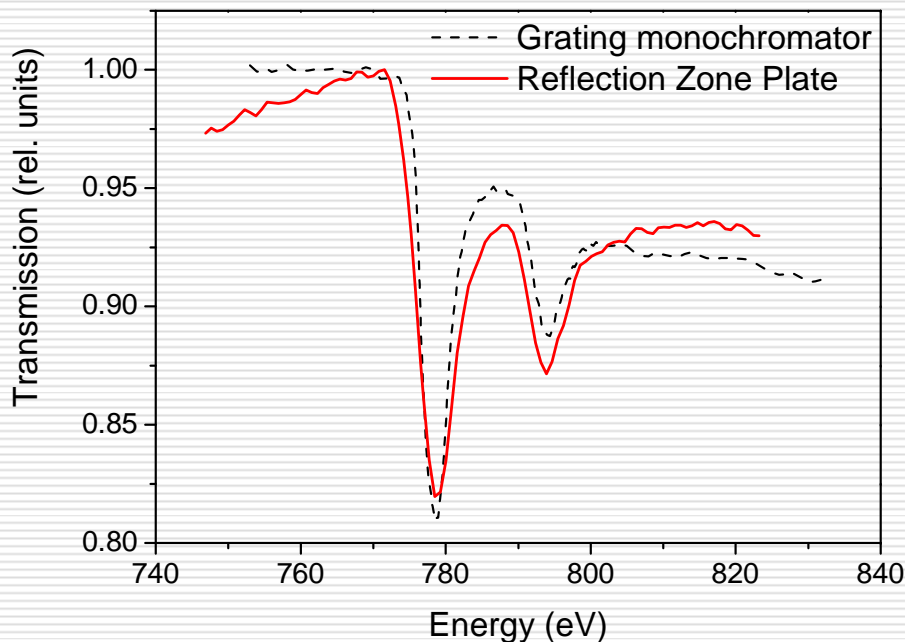


Beamline optics focal spot: $\sim 300 \mu\text{m}$ (H) x $25 \mu\text{m}$ (V)
 Energy dispersion in focal plane: $\sim 40 \text{ eV} / \text{mm}$
 Total beamline optics transmittance: $\sim 6.5\%$
 Time resolution of beamline optics: $\sim 30 \text{ fsec}$

Reflection Zone Plates for fs XAS

Combination on the same optical element
the reflection, focusing and dispersion.

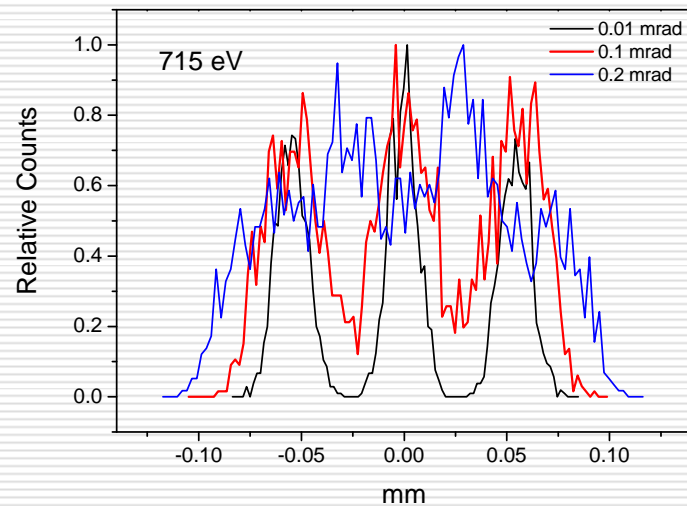
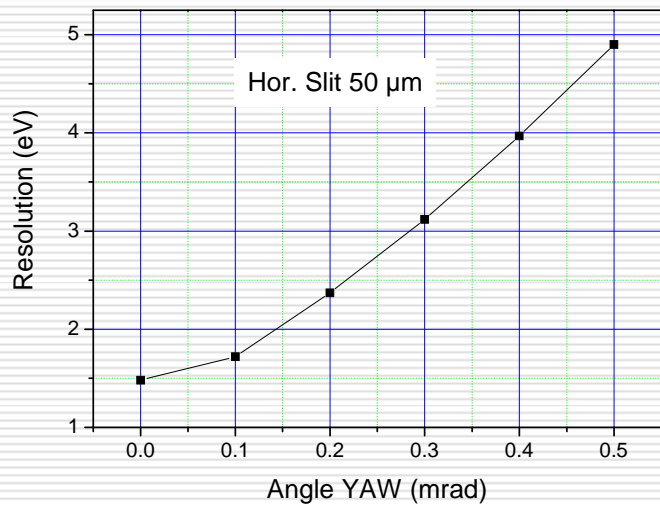
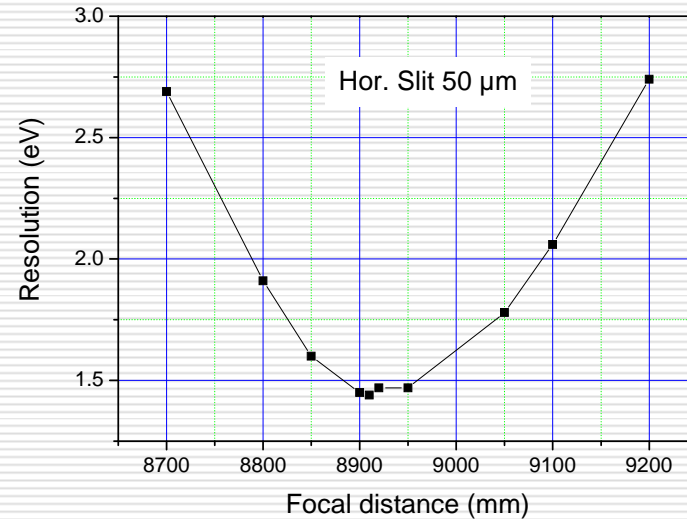
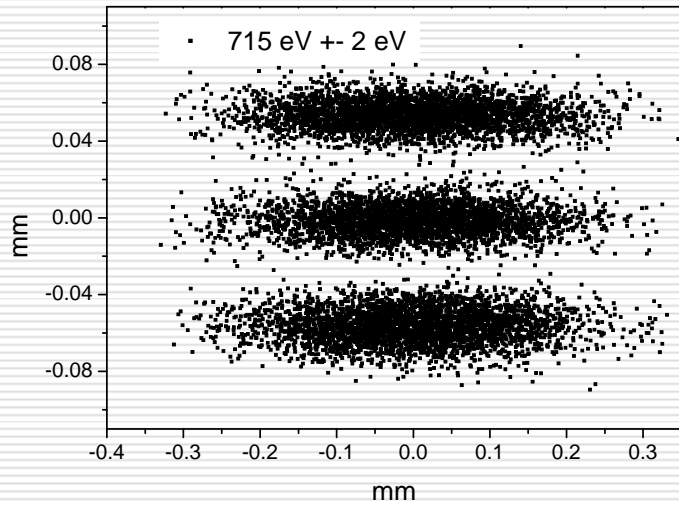
- Extremely high radiation stability: $> 10 \text{ GW} / \text{mm}^2$
- Time resolution: $< 30 \text{ fsec}$
- Integral efficiency: $> 10\%$
- Energy dispersion in focal plane: $\sim 40 \text{ eV} / \text{mm}$



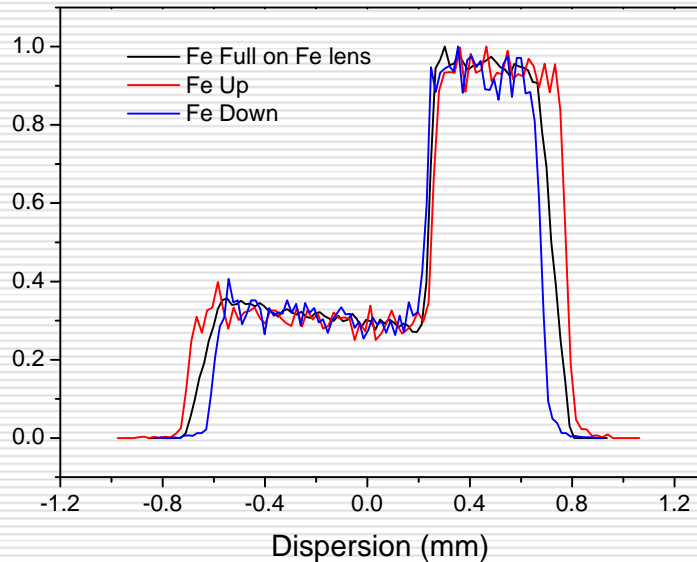
Gold reflection off-axis zone plates on a Si substrate: 715 eV, 785 eV, 861 eV.
Focal distance: 902 cm. Outer zone: 1 μm . Aperture: 80 mm x 10 mm

Lenses groove depth is 14 nm.

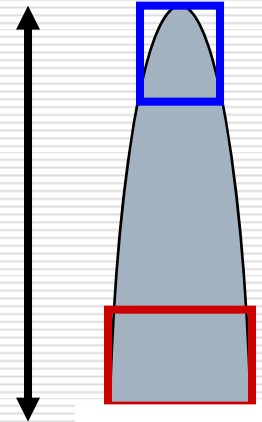
RAY RZP code application: fs RZP focal plane



RAY code application: Absorption spectra on Fe and Co

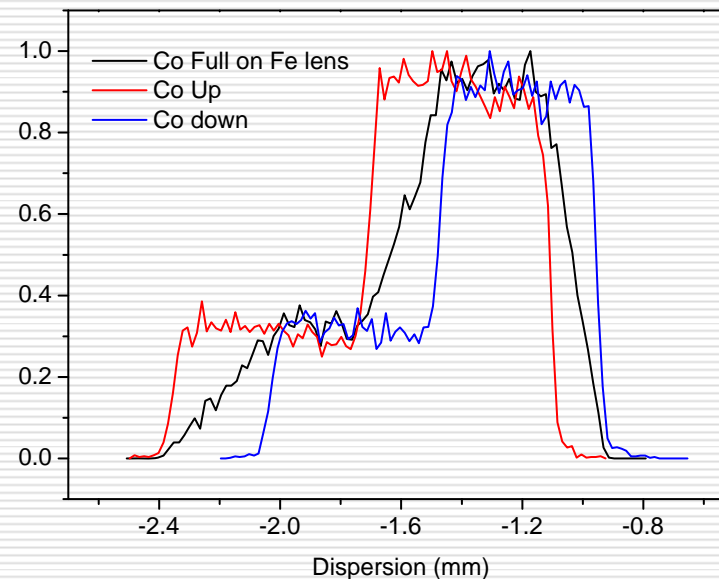


Absorption $L\alpha$ spectra of the Fe on a Fe-designed RZP



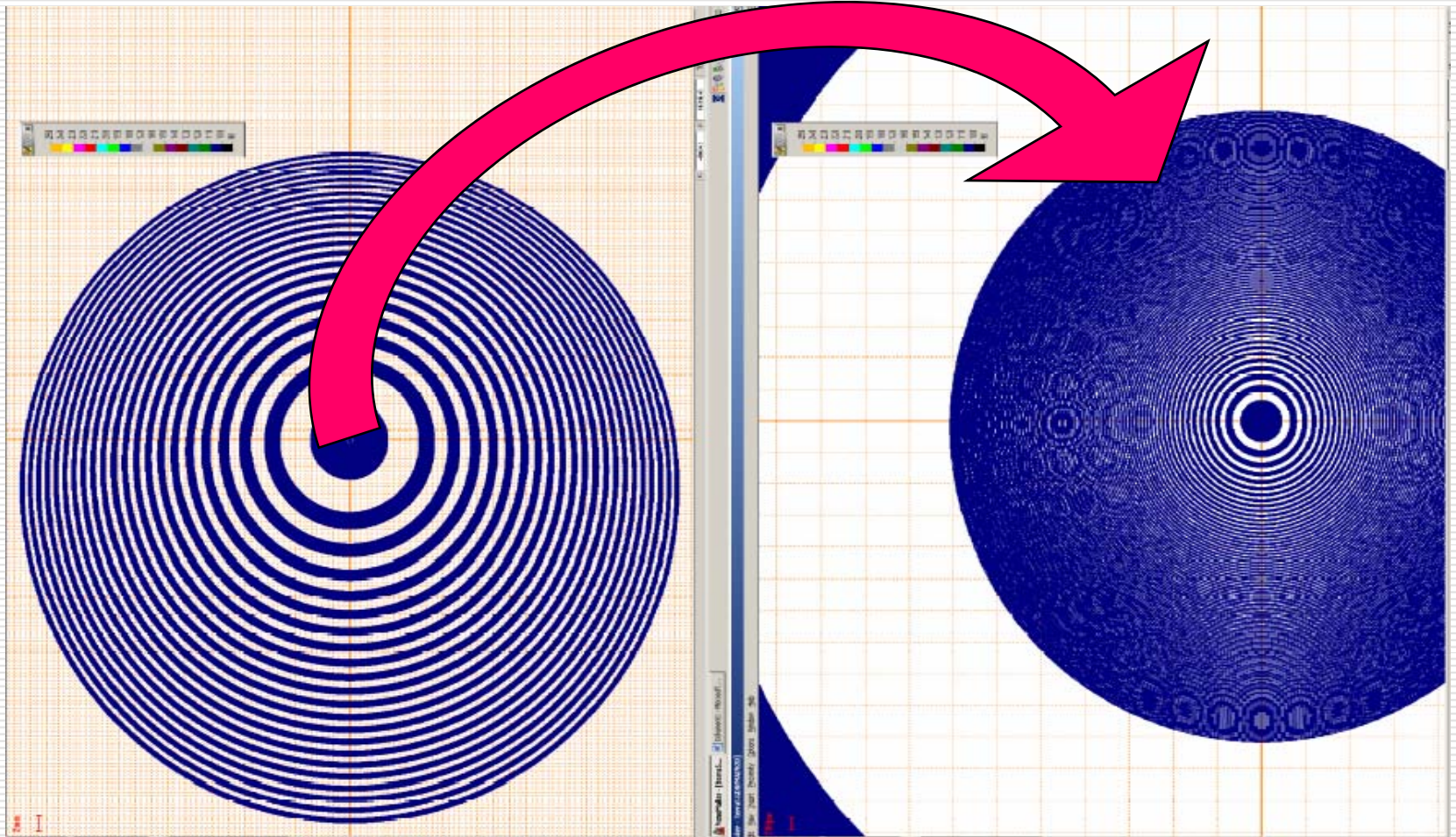
Different irradiated areas on a zone plate

Absorption $L\alpha$ spectra of the Co on a Fe-designed RZP



Lens for Terahertz radiation.

Wavelength is $200\ \mu\text{m}$, focus distance is 10 cm.

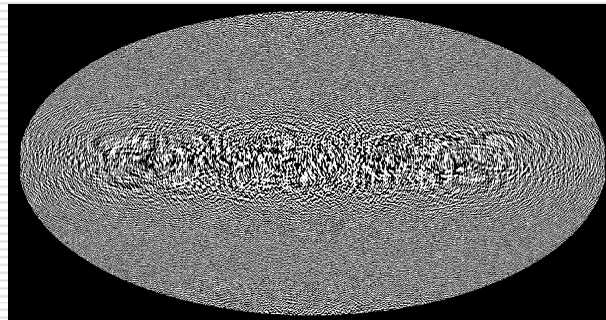


Synthetic holograms. Reconstruction.

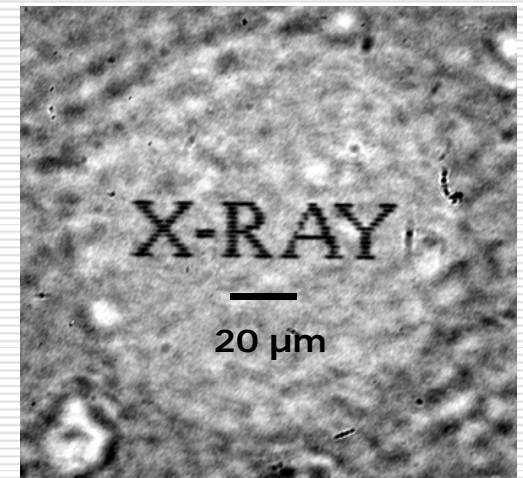


Computer-generated
"virtual" image

Computer-generated
hologram



Reconstructed image



Thank you!